

August 2012

FDME0106NZT

N-Channel PowerTrench® MOSFET 20 V, 9 A, 18 m Ω

Features

- Max $r_{DS(on)}$ = 18 m Ω at V_{GS} = 4.5 V, I_D = 9 A
- Max $r_{DS(on)} = 24 \text{ m}\Omega$ at $V_{GS} = 2.5 \text{ V}$, $I_D = 7.5 \text{ A}$
- Max $r_{DS(on)}$ = 32 m Ω at V_{GS} = 1.8 V, I_D = 7 A
- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level >2.5 kV (Note3)
- RoHS Compliant

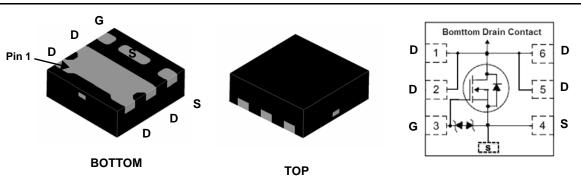


General Description

This Single N-Channel MOSFET has been designed using Fairchild Semiconductor's advanced Power Trench process to optimize the $r_{DS(ON)}$ @ VGS = 1.8 V on special MicroFET leadframe.

Applications

- Li-Ion Battery Pack
- Baseband Switch
- Load Switch
- DC-DC Conversion



MicroFET 1.6x1.6 Thin

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Paramet	Parameter			
V_{DS}	Drain to Source Voltage	Drain to Source Voltage			
V _{GS}	Gate to Source Voltage			±12	V
	Drain Current -Continuous	T _A = 25 °C	(Note 1a)	9	^
I _D	-Pulsed			40	Α
Б	Power Dissipation for Single Operation	T _A = 25 °C	(Note 1a)	2.1	10/
P_{D}	Power Dissipation for Single Operation	T _A = 25 °C	(Note 1b)	0.7	W
T _{.I} , T _{STG}	Operating and Storage Junction Temperation	ure Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	70	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	190	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
8T	FDME0106NZT	MicroFET 1.6x1.6 Thin	7 "	8 mm	5000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		20		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 12 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	0.5	0.8	1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25 °C		-3		mV/°C
		$V_{GS} = 4.5 \text{ V}, I_D = 9 \text{ A}$		14	18	
		$V_{GS} = 2.5 \text{ V}, I_D = 7.5 \text{ A}$		17	24	
r _{DS(on)}	r _{DS(on)} Drain to Source On Resistance	$V_{GS} = 1.8 \text{ V}, I_D = 7 \text{ A}$		26	32	mΩ
	$V_{GS} = 4.5 \text{ V}, I_D = 9 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$		19	24		

Dynamic Characteristics

C _{iss}	Input Capacitance	V 40.V V 0.V	865	pF
Coss	Output Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	203	рF
C _{rss}	Reverse Transfer Capacitance	1 - 1 101112	190	pF
R _a	Gate Resistance		1.0	Ω

Switching Characteristics

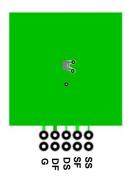
t _{d(on)}	Turn-On Delay Time		9	ns
t _r	Rise Time	V _{DD} = 10 V, I _D = 4 A	5	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 2 \Omega$	19	ns
t _f	Fall Time		5	ns
Q_g	Total Gate Charge	$V_{DD} = 4.2 \text{ V}, I_D = 3 \text{ A}, V_{GS} = 4.3 \text{ V}$	8.0	nC
Qg	Total Gate Charge	$V_{DD} = 4.2 \text{ V}, I_D = 3 \text{ A}, V_{GS} = 4.5 \text{ V}$	8.5	nC
Q _{gs}	Gate to Source Gate Charge	V 40 V 1 0 A	1.4	nC
Q_{gd}	Gate to Drain "Miller" Charge	V _{DD} = 10 V, I _D = 9 A	3.2	nC

Drain-Source Diode Characteristics

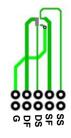
V _{SD} Source to Drain Diode Forward Voltage	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.6 \text{ A}$	(Note 2)	0.7	1.2	V
	$V_{GS} = 0 \text{ V}, I_{S} = 9 \text{ A}$	(Note 2)	8.0	1.2	V	
t _{rr}	Reverse Recovery Time	F = 9 A, di/dt = 100 A/us		18		ns
Q _{rr}	Reverse Recovery Charge			4		nC

Notes

^{1.} R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



 a. 70 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 190 °C/W when mounted on a minimum pad of 2 oz copper.

^{2.} Pulse Test: Pulse Width < 300 $\mu s, \, \text{Duty cycle} < 2.0\%.$

^{3.} The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

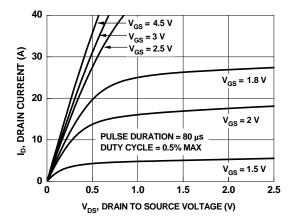


Figure 1. On Region Characteristics

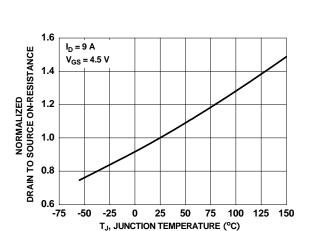


Figure 3. Normalized On Resistance vs Junction Temperature

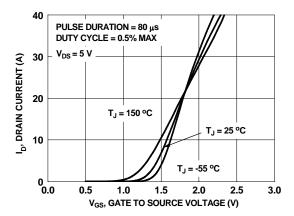


Figure 5. Transfer Characteristics

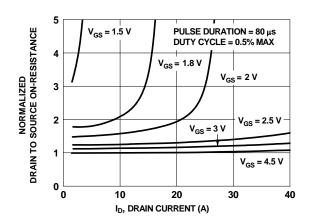


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

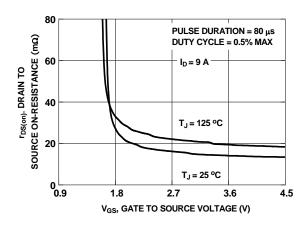


Figure 4. On-Resistance vs Gate to Source Voltage

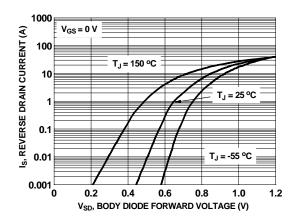


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

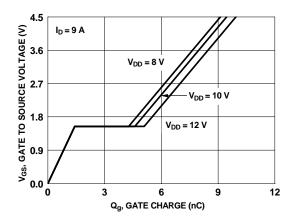


Figure 7. Gate Charge Characteristics

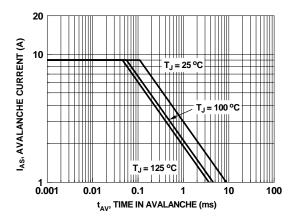


Figure 9. Unclamped Inductive Switching Capability

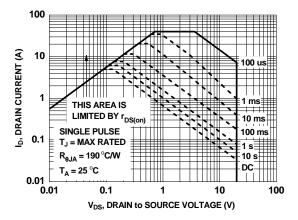


Figure 11. Forward Bias Safe Operating Area

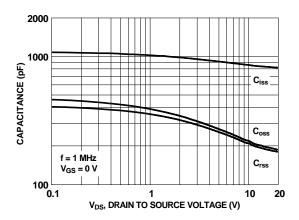


Figure 8. Capacitance vs Drain to Source Voltage

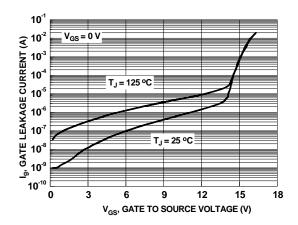


Figure 10. Gate Leakage Current vs Gate to Source Voltage

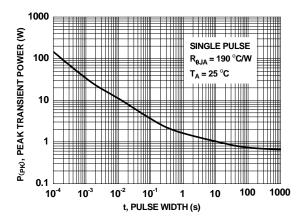


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

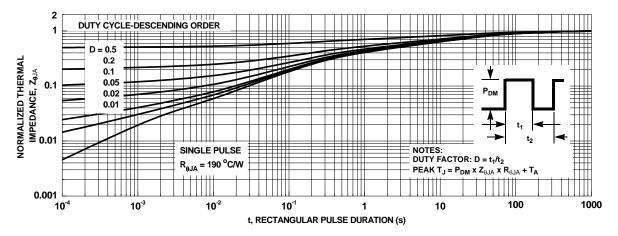
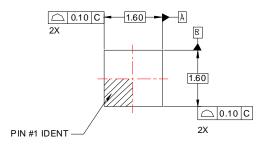
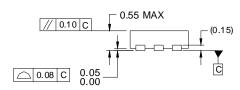


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

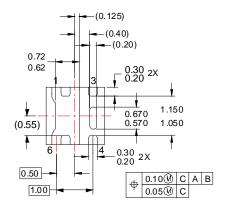
Dimensional Outline and Pad Layout



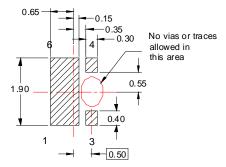
TOP VIEW



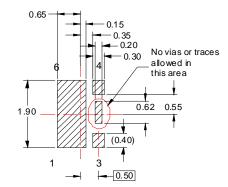
SIDE VIEW



BOTTOM VIEW



RECOMMENDED LAND PATTERN OPT 1



RECOMMENDED LAND PATTERN OPT 2

NOTES:

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- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
- D. LAND PATTERN RECOMMENDATION IS BASED ON FSC DESIGN ONLY
- E. DRAWING FILENAME:





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